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IFW 2621

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunji MAEDA *et al.*
Serial No. : 09/294,137
Filed : 20 April 1999
For : DEFECT INSPECTION METHOD AND APPARATUS
Group AU : 2621
Examiner : B.P. Werner
Conf. No. : 5815

AMENDMENT

Mail Stop Amendment

Commissioner for Patents

P.O. Box 1450

Alexandria, Virginia 22313-1450

13 December 2004

Sir:

In response to the Office Action mailed 13 July 2004 in connection with the above-identified application, the following amendments and remarks are respectfully submitted.

In accordance with the manner of making amendments under 37 CFR §1.121 as set forth in the Final Rule effective 30 July 2003, and as revised in the Final Rule effective 21 October 2004, each section of amendment begins on a new page, and changes are shown by strike-through (or double brackets) and underlining to indicate deletions and additions, respectively. A complete listing of all claims ever presented in the application is given with the current status of each claim, and the text of all pending and withdrawn claims is presented in full, with those not being amended herein being presented in clean version.